

**Fault management instrumentation network based on IEEE P1687 JTAG**

**Shibin, Konstantin; Jutman, Artur; Devadze, Sergei** European Test Symposium (ETS), 2013, Avignon, France 2013

**FP7 DIAMOND : design error diagnosis and correction success stories**

**Raik, Jaan; Jenihhin, Maksim; Könighofer, Robert** European Test Symposium (ETS), 2013, Avignon, France 2013 / p. 1-6